

ABSTRACT OF THE DISCLOSURE

State data from a circuit 2 is saved to a memory 14 via a system bus 4, 6, 8, 10 under control of a state saving controller 16. The state data may be captured within
5 scan chains 12 provided for production test within the circuit with these scan chains supplying respective bits to the multi-bit state saving data words that are stored to the memory via the system bus.

[Figure 3]